

PATENTS

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Takehiko HAMADA

Serial No. 09/057,455

Filed April 9, 1998



GROUP 2878

Examiner J. Berman

Arlene
4/12/00
7/a

POSITION DETECTING SYSTEM AND
METHOD

AMENDMENT

Assistant Commissioner for Patents

Washington, D.C. 20231

Sir:

Responsive to the Official Action of October 6,
1999, please amend the above-identified application as
follows:

IN THE SPECIFICATION:

Page 2, line 21, change "103" to --104--;

line 24, change "103" to --104--.

Page 3, line 2, cancel "a".

Page 12, line 18, change "14" to --13--.

IN THE CLAIMS:

Amend claim 1 as follows:

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--1. (amended) A position detecting system
comprising a beam irradiating means for irradiating an
electron beam to a sample including a portion to be measured,
a beam scanning means for relatively scanning the electron
beam so that the electron beam moves in relation to the
portion to be measured in the sample, a voltage applying means